

SHEET 1 OF 1

Substitute Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEDOCKET  
HDS008S.N.  
10/674,805

## INFORMATION DISCLOSURE STATEMENT

APPLICANT  
Milton W. Demaray, et al.FILING DATE  
September 29, 2003GROUP  
2113

## U.S. PATENT DOCUMENTS

*Exam. Initial	Cite No.	DOCUMENT NUMBER Number - Kind Code	PUBLICATIO N DATE	NAME OF PATENTEE OR APPLICANT	FILING DATE
SS		US- 2003/0115433 A1	6-19-03	Kodama	12-14-01
		US-5,459,857	10-17-95	Ludlam, et al.	9-27-94
		US-6,189,079 B1	2-13-01	Micka, et al.	5-22-98
		US-2003/0131278 A1	7-10-03	Fujibayashi	1-10-02
		US-			
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## FOREIGN PATENT DOCUMENTS

*Exam. Initial	Cite No.	DOCUMENT NUMBER Number - Kind Code	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	TRANSLATION YES NO	

## NON-PATENT LITERATURE DOCUMENTS

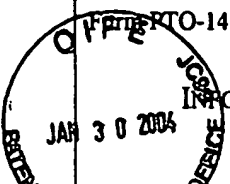
*Exam. Initial	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	TRANSLATION YES NO	

EXAMINER

DATE CONSIDERED

6/23/2006

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP; draw line through citation if not in conformance and not considered. Include copy of this form with next communication with applicant.

	PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	DOCKET HDS008	S.N. 10/674,805
	INFORMATION DISCLOSURE STATEMENT			
	APPLICANT Milton W. Demaray, et al.		FILING DATE September 29, 2003	

## U.S. PATENT DOCUMENTS

		DOCUMENT NUMBER							DATE	NAME	CLASS	SUB-CLASS	FILING DATE
<i>SS</i>		5	8	2	2	7	7	3	10-13-98	Pritchard et al.			10-17-96
		6	1	5	7	9	9	1	12-05-00	Armon			04-01-98
		6	2	6	9	4	3	1	07-31-01	Dunham			08-13-98
		6	2	8	9	3	9	8	09-11-01	Stallmo et al.			07-27-98
		6	2	9	5	5	7	5	09-25-01	Blumenau et al.			06-29-98
		6	3	0	8	2	8	4	10-23-01	LeCrone et al.			08-28-98
		6	3	2	4	6	5	4	11-27-01	Wahl et al.			03-30-98
		6	3	5	6	9	7	7	03-12-02	Ofek et al.			12-12-00
		6	4	0	5	2	9	4	06-11-02	Hayter			12-29-95
		6	4	0	8	3	6	9	06-18-02	Garrett et al.			03-12-98
		6	5	1	3	1	0	2	01-28-03	Garrett et al.			04-30-02
		6	5	2	9	9	9	5	03-04-03	Shepherd			06-18-99
		6	5	3	9	4	6	1	03-25-03	Suzuki et al.			03-24-99
		6	6	2	9	2	6	4	09-30-03	Sicola et al.			03-30-00
		6	6	4	3	6	6	7	11-04-03	Arai et al.			03-17-00
		6	6	4	7	4	6	0	11-11-03	Kodama			07-13-01
	2002	0	0	8	3	2	6	3	06-27-02	Petruschka et al.			12-21-00
	2003	0	1	4	9	7	3	6	08-07-03	Berkowitz et al.			02-07-02
	2003	0	1	7	7	3	2	3	09-18-03	Popp et al.			01-11-02
	2003	0	1	8	8	1	1	4	10-02-03	Lubbers et al.			03-26-02
	2003	0	1	9	6	0	5	2	10-16-03	Bolik et al.			04-10-02

## FOREIGN PATENT DOCUMENTS

*Exam. Initial		DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES NO	

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)


EXAMINER <i>[Signature]</i>	DATE CONSIDERED <i>6/23/2006</i>
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